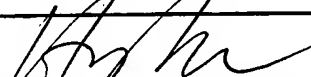


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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Substitute for Form 1449B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	Unknown
				Filing Date	Herewith
				First Named Inventor	Donald J. Svetkoff, et al.
				Group Art Unit	Unknown
				Examiner Name	Unknown
Sheet	3	of	3	Attorney Docket Number	GSIL 0186 PUS 3
OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
WSP		Brochure NM-2654A Panasert IP-K-V, "The Rotating Mirror Scan System Inspects Large High-Density PC Boards Quickly and Precisely", Specifications			
WSP		"Dynamic Focusing in the Confocal Scanning Microscope", T. Wilson and D.K. Hamilton, Journal of Microscopy, Vol. 128, Pt. 2, November 1992, pp. 139-143			
WSP		"Digital Image Processing of Confocal Images", I. J. Cox and C.J.R. Sheppard, Image and Vision Computing, Vol. 1. No. 1, February 1983, pp. 52-56			
WSP		"Three-Dimensional Surface Measurement Using the Confocal Scanning Microscope", D.K. Hamilton and T. Wilson, Appl. Phys. B 27.211-213 (1982)			
WSP		"Scanning Optical Microscope Incorporating A Digital Framestore and Microcomputer", I.J. Cox and C.R. Sheppard. Applied Optics, Vol. 22, No. 10, May 15, 1983, pp. 1474-1478			
WSP		"Depth of Field in the Scanning Microscope", C.J.R. Sheppard and T. Wilson, Optics Letters, September 1978. Vol. 3, No. 3, pp. 115-117			
WSP		"NLB Laser Inspector, NLB-7700M Specifications", Nagoya Electric Works Co., Ltd. December 1994			
WSP		"Automatic Inspection of Component Boards Using 3D and Greyscale Vision", Donald J. Svetkoff, David N. Smith and Brian L. Doss, Proceedings of the 1986 International Symposium on Microelectronics, pp. 57-64			

Examiner Signature		Date Considered	4/5/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.